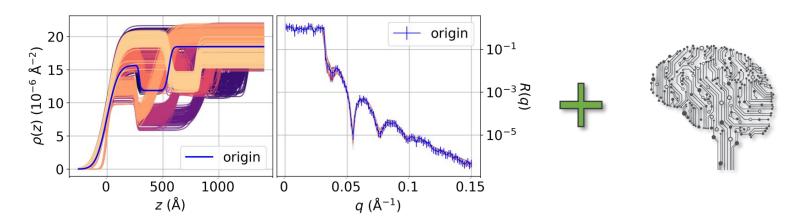
Machine learning for reflectometry: Resolving ambiguity

Vladimir Starostin and Frank Schreiber http://www.soft-matter.uni-tuebingen.de

A. Greco, V. Munteanu, C. Völter, M. Romodin, D. Lapkin, L. Pithan, A. Gerlach, A. Hinderhofer et al.



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- 1. mlreflect 1.0 recap
- 2. mlreflect 2.0 ML + prior knowledge
- 3. mlreflows (3.0) probabilistic ML approach

special thanks to
S. Kowarik group
synchrotrons
neutron facilities
ML excellence cluster





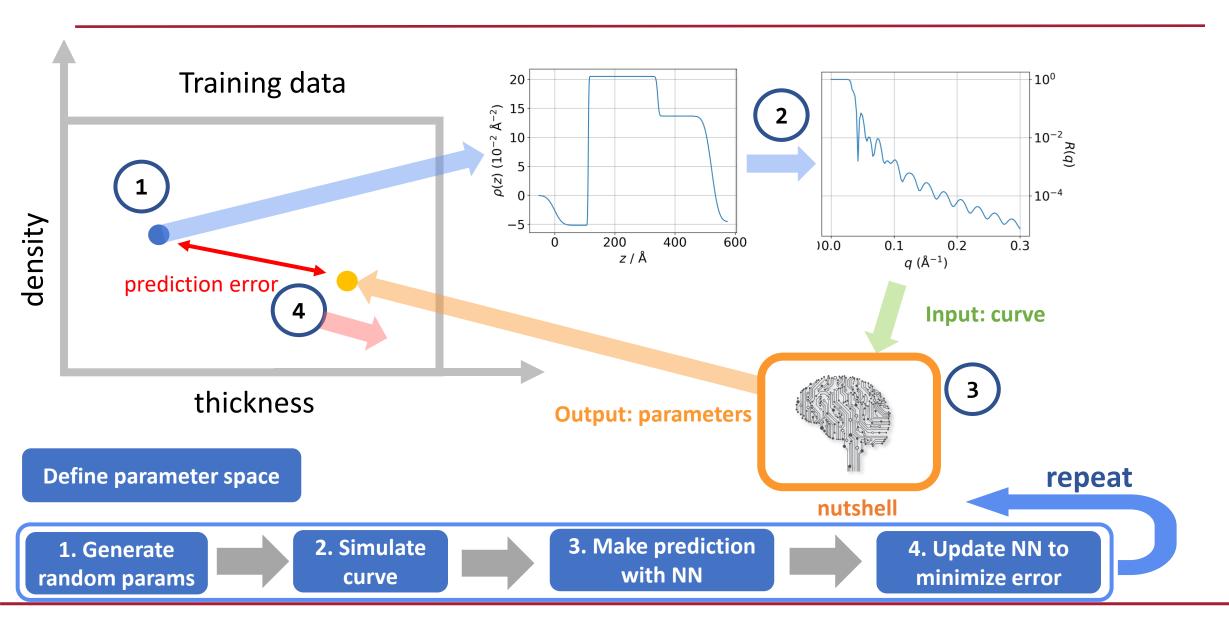


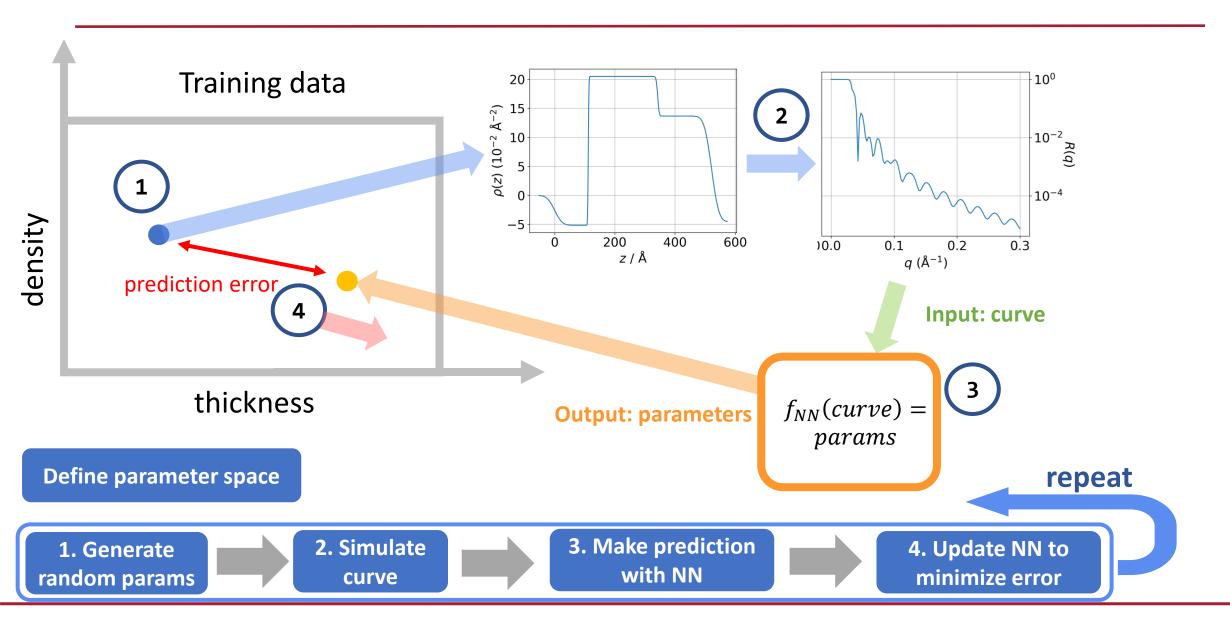


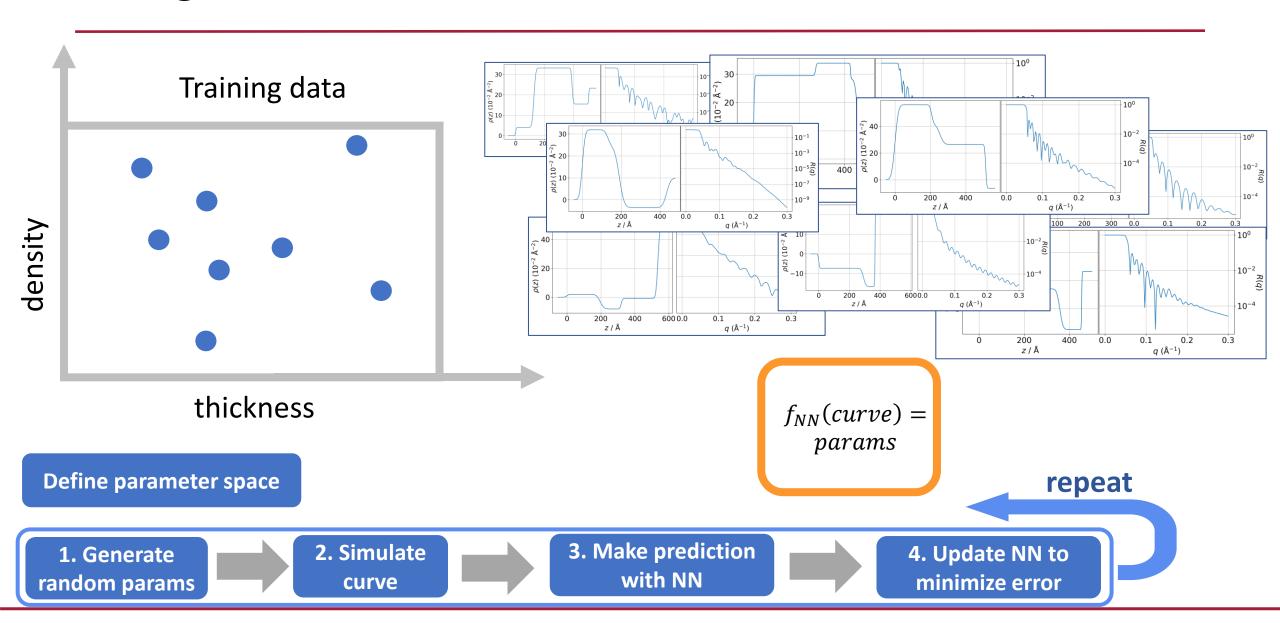


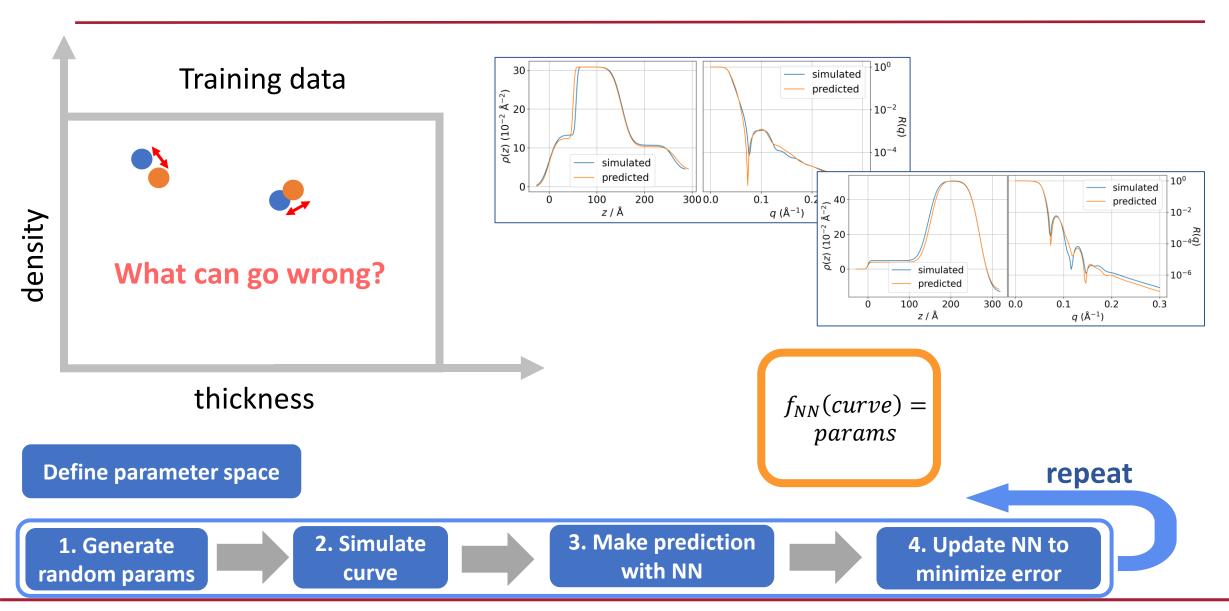
Standard Machine Learning approach (mlreflect 1.0)

Why mlreflect does not scale to higher number of parameters?

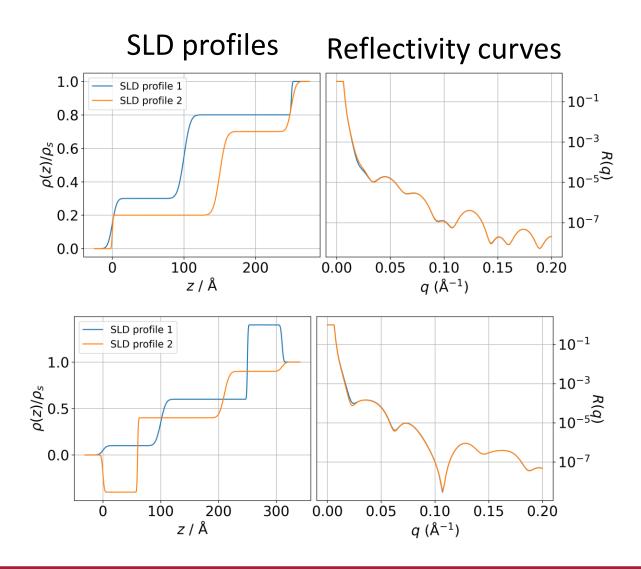






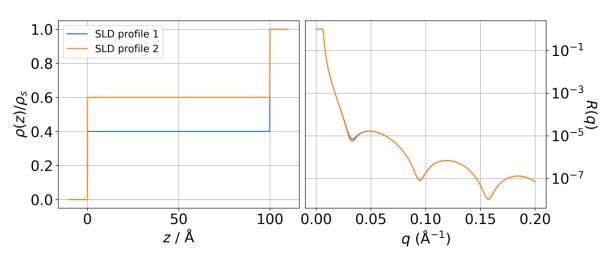


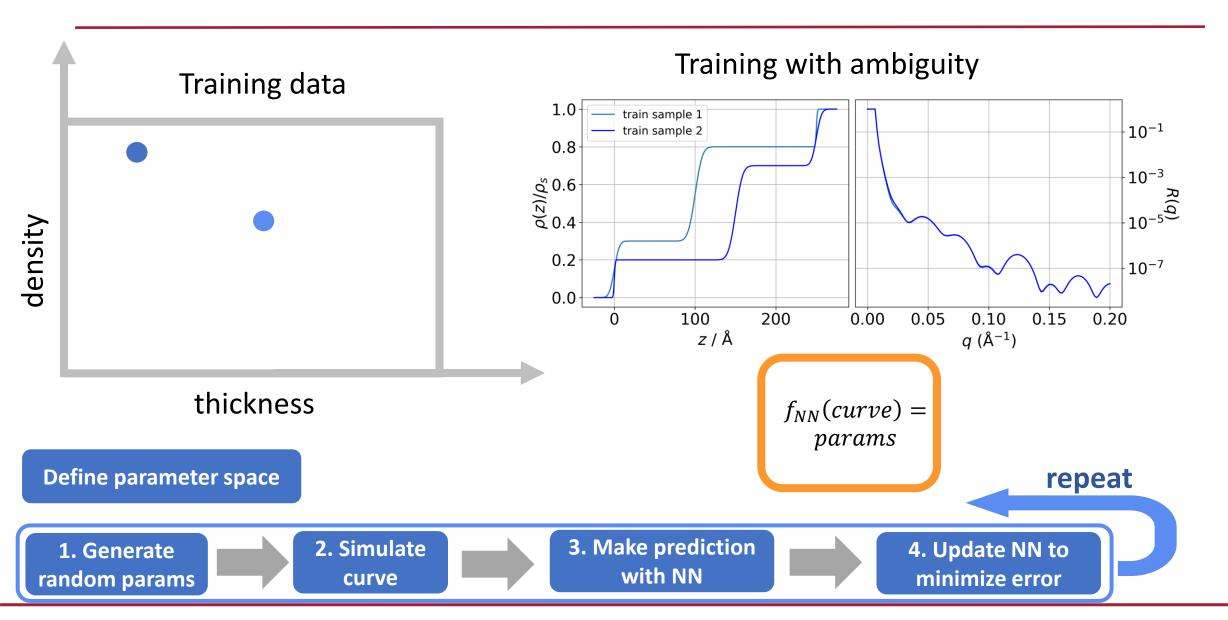
Ambiguity in the reflectometry data (theoretical examples)

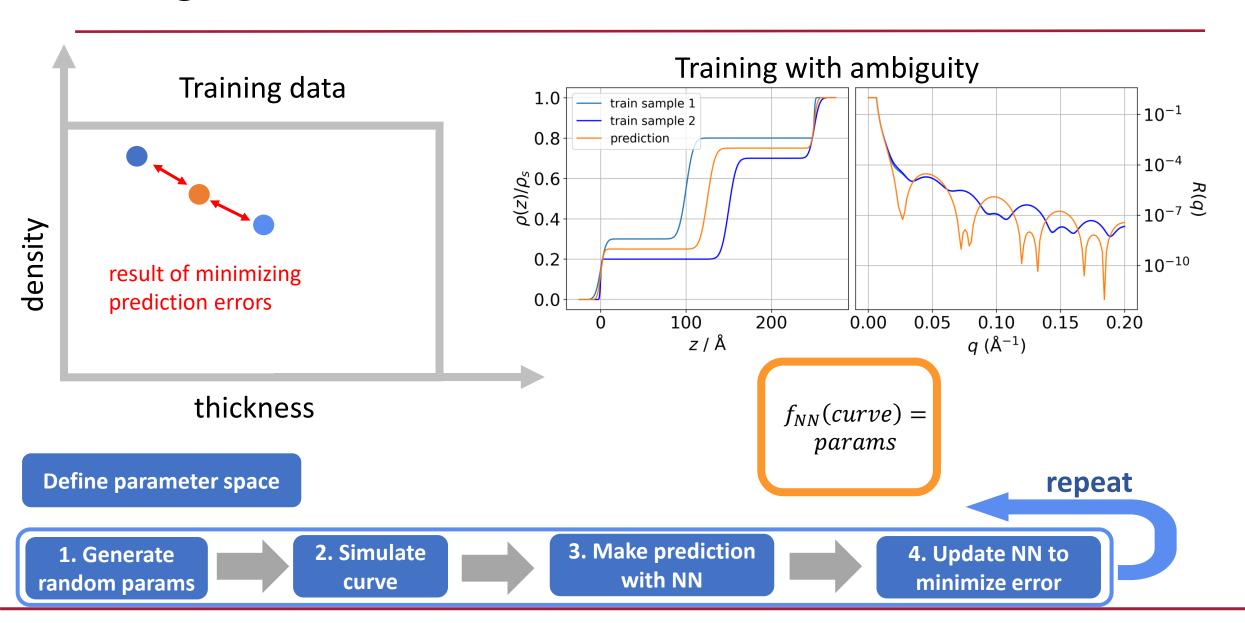


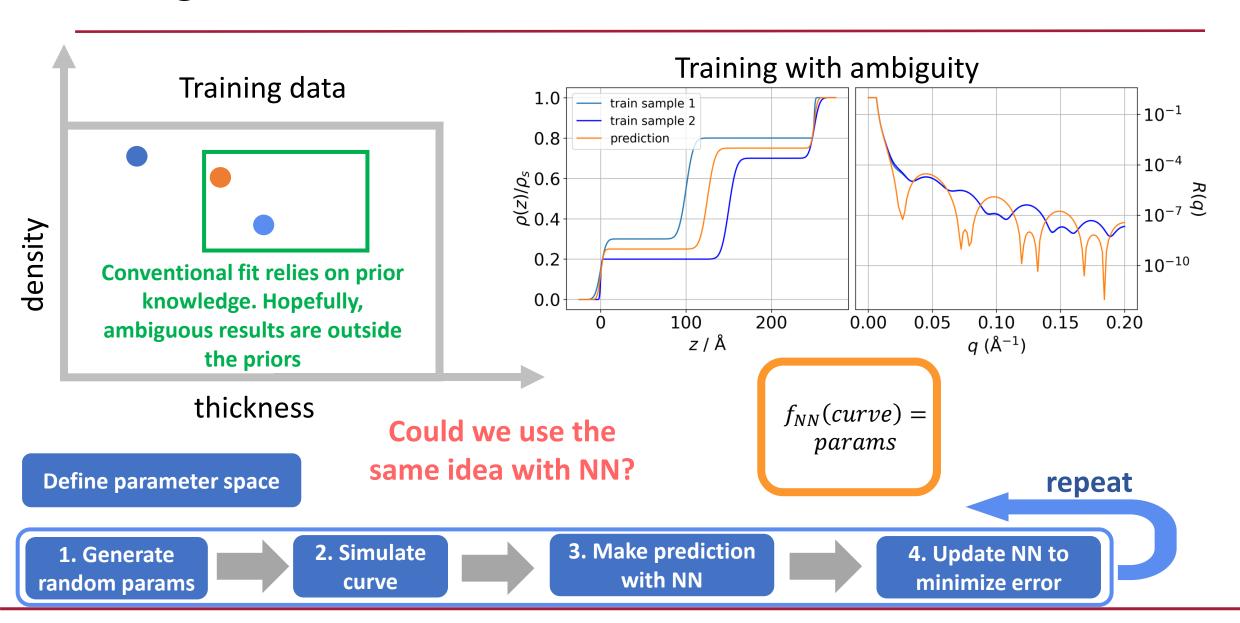
Reasons for the ambiguity:

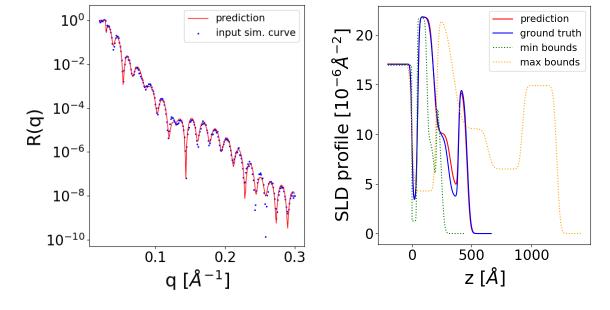
- "Phase" problem
- Noise (counting statistics)
- Finite *q* range
- Finite number of q points
- •







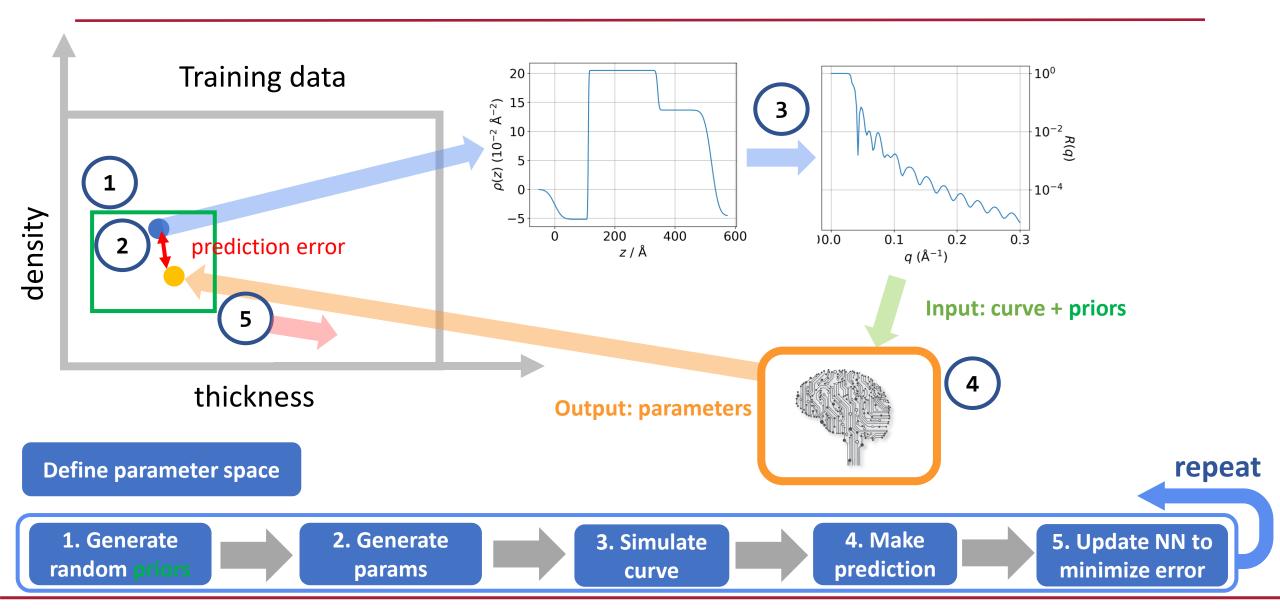


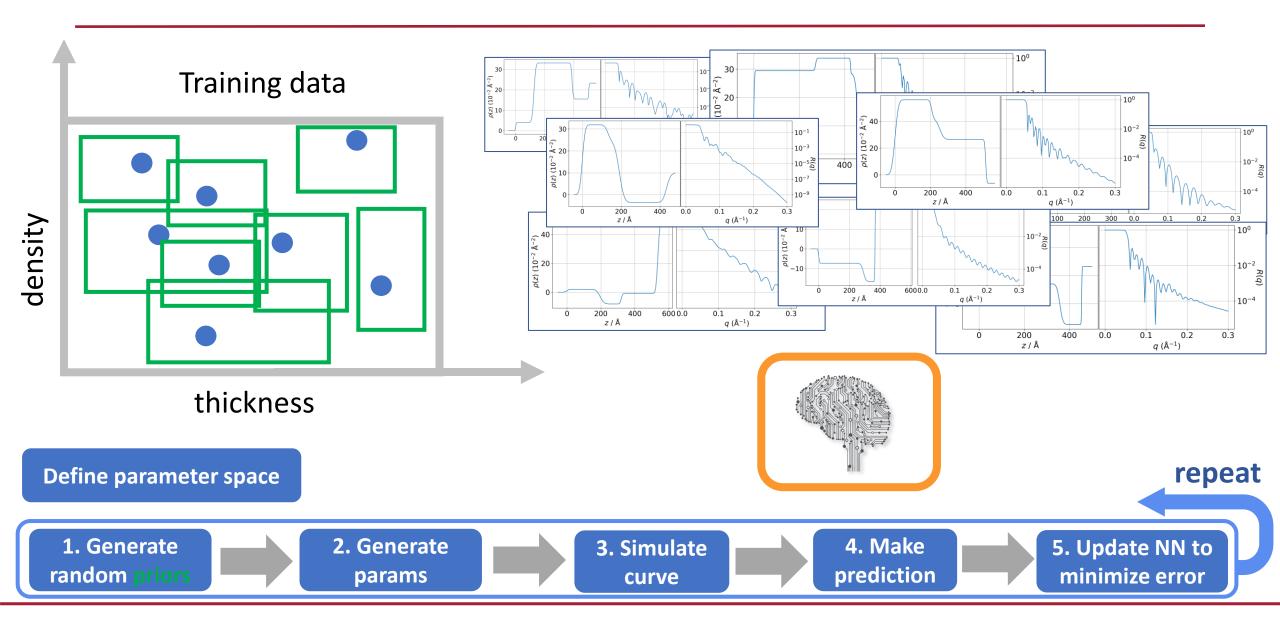


Machine Learning + Prior Knowledge (mlreflect 2.0)

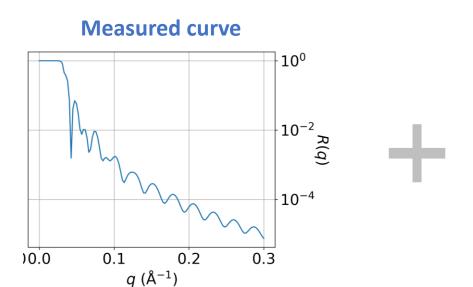
Addressing ambiguity by incorporating physical knowledge into the model

Training mlreflect 2.0





mlreflect 2.0 from a user's perspective



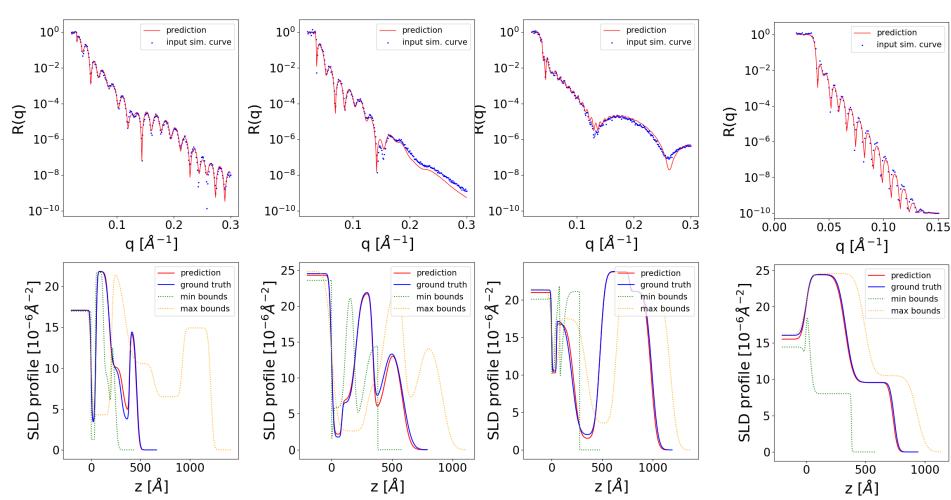
Parameter ranges - additional input

Parameter	Min value	Max value
d_1	10.	50.
$ ho_1$	15.1	15.3
σ_1	0.	40.

params = model.predict(input=(refl_curve, param_ranges))

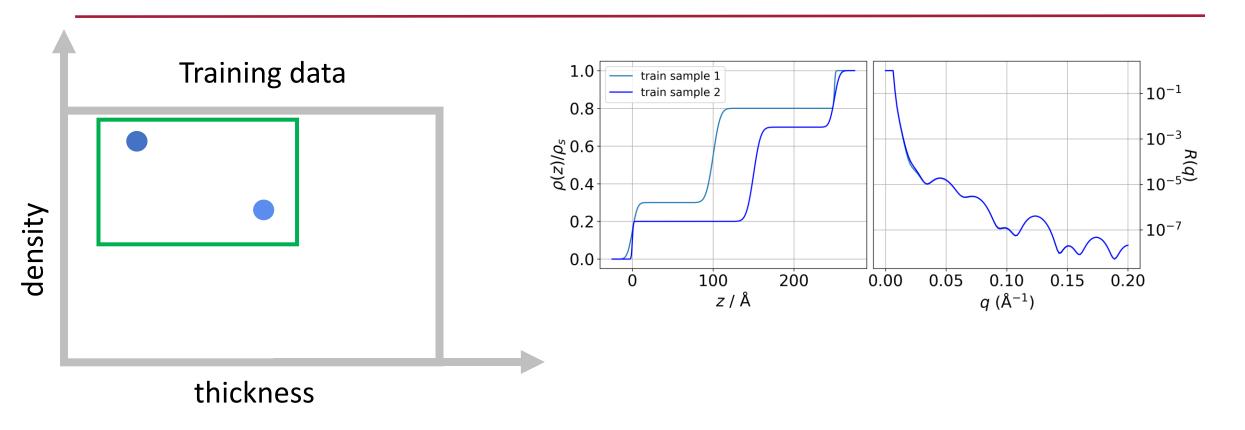
mlreflect 2.0 - complex scenarios with multiple layers

Single model, different sample-dependent parameter ranges



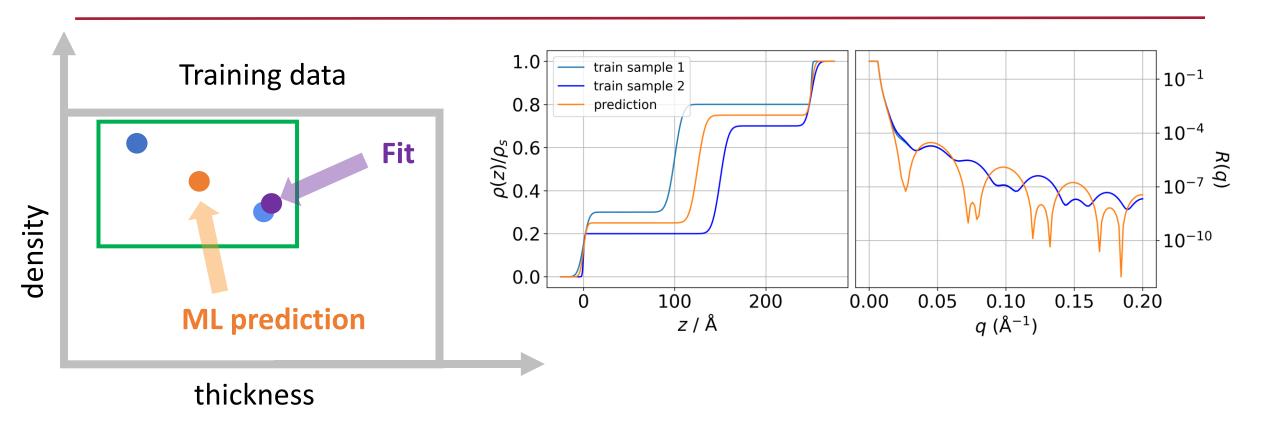
- Works with high number of parameters (tested up to 17)
- No postprocessing (can be improved further by gradient descent)
- Real-time (milliseconds)
- If the ranges are wide enough to include ambiguous results, both ML and conventional fit will fail.

Both mlreflect 2.0 and conventional fit fail in case of ambiguity



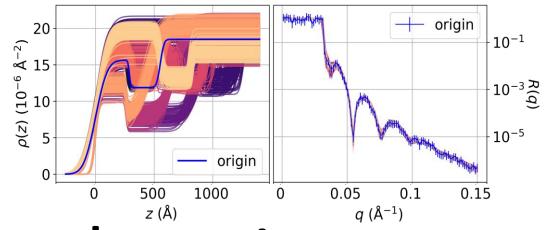
Both solutions might be physically correct, and these methods only provide one.

Both mlreflect 2.0 and conventional fit fail in case of ambiguity



Both solutions might be physically correct, and these methods only provide one.

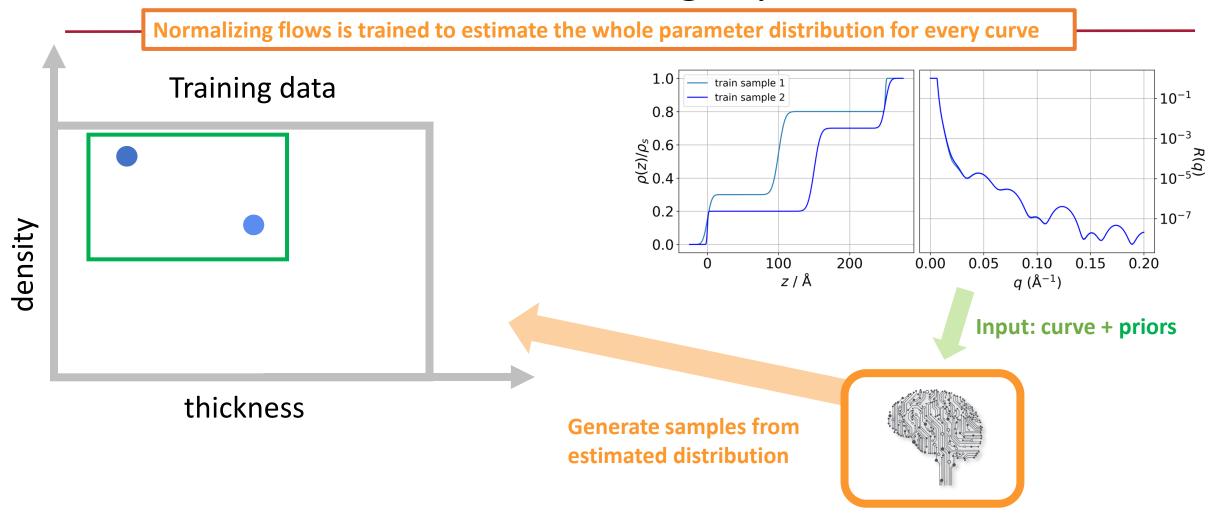
To get all the solutions, we need probabilistic methods (Bayesian analysis)



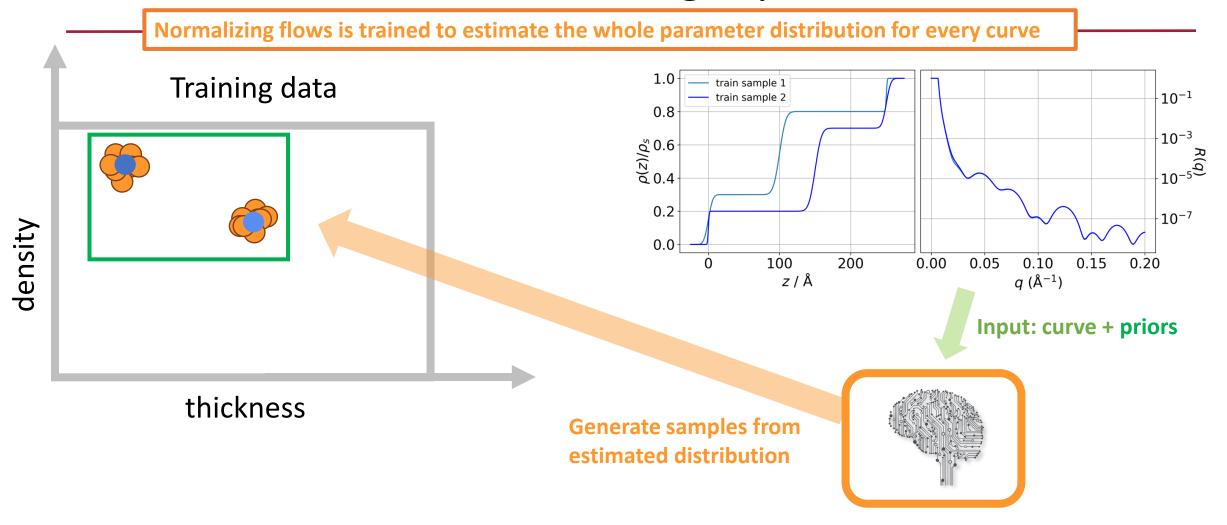
Probabilistic machine learning approach to reflectometry – mlreflows (3.0)

Fast, accurate, reliable Bayesian reflectometry analysis with normalizing flows

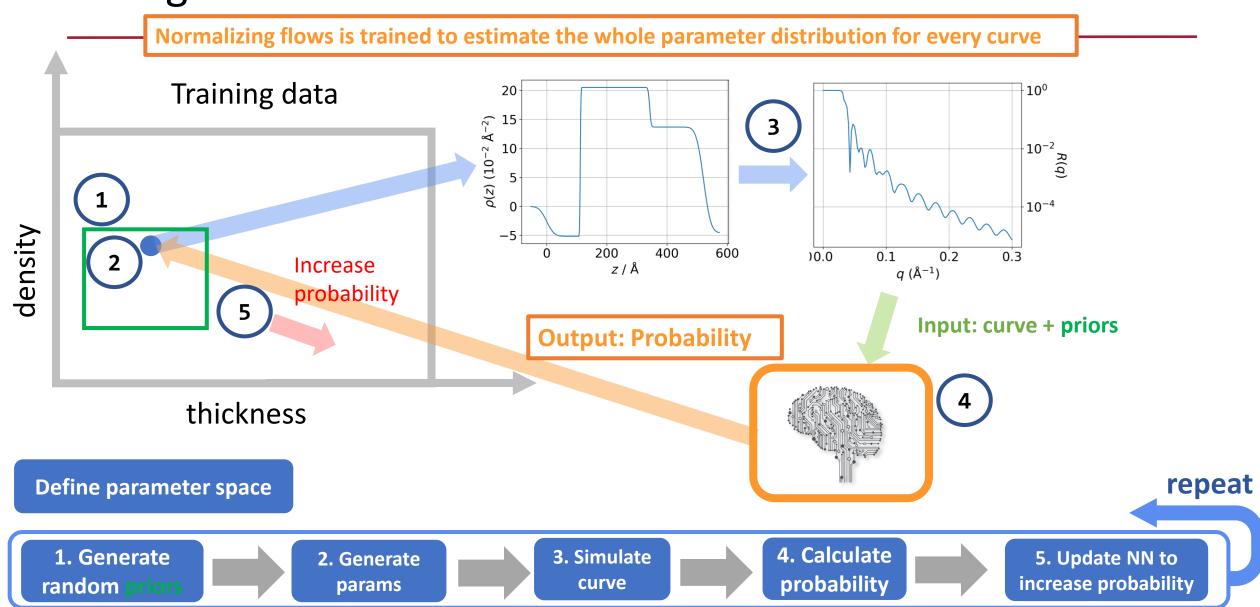
How mlreflows resolves ambiguity



How mlreflows resolves ambiguity



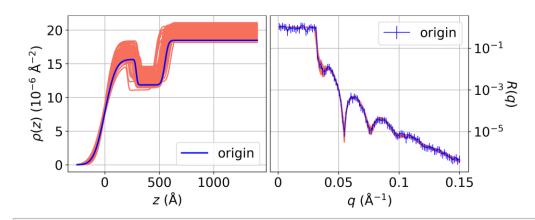
Training mlreflows



mlreflows from a user's perspective

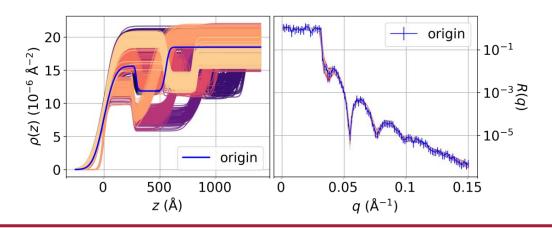
model.sample(num_samples, input=(refl_curve, narrow_param_ranges))

Narrow range



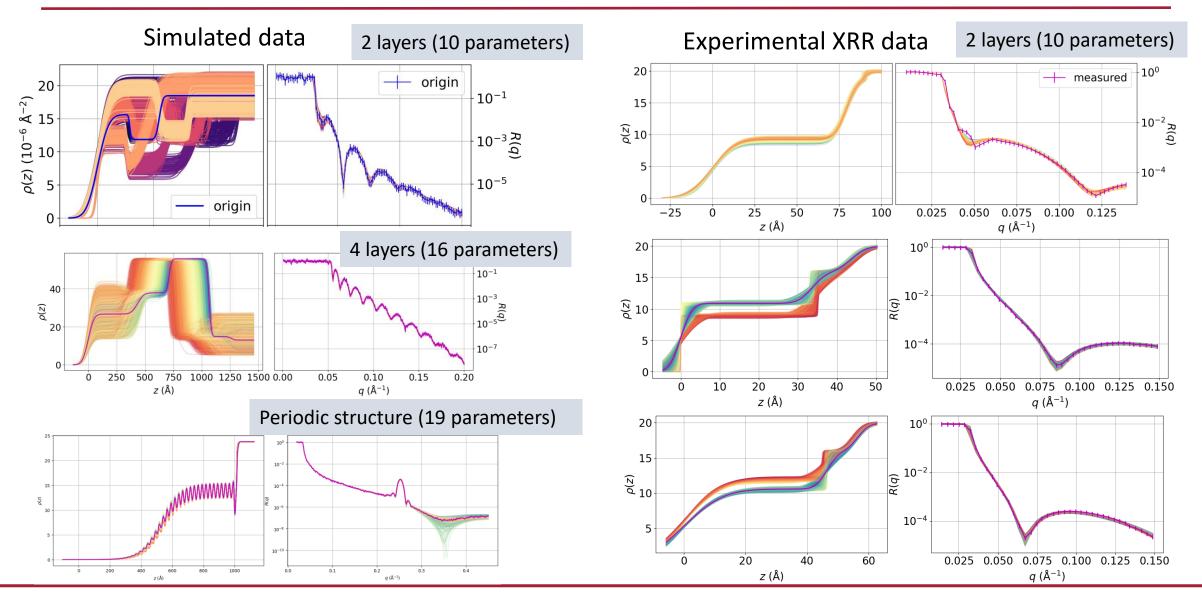
model.sample(num_samples, input=(refl_curve, wide_param_ranges))

Wide range



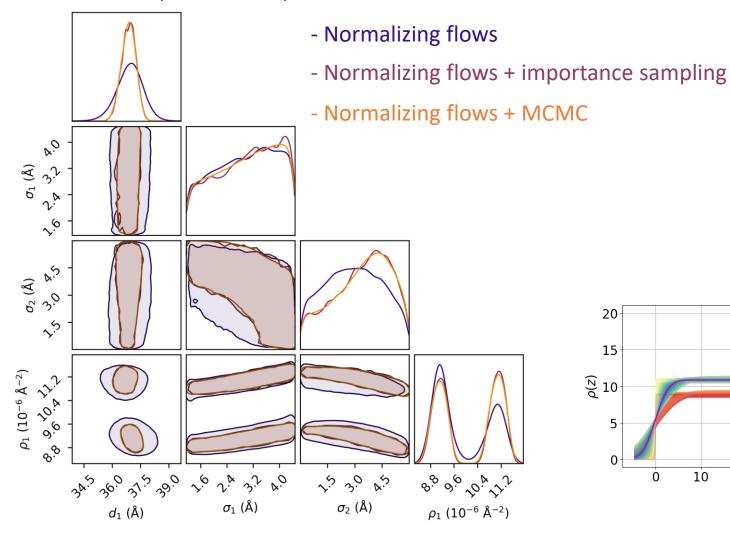
Unlike mlreflect 2.0, it does not fail in the case of ambiguity. It provides all the solutions!

mlreflows - complex scenarios



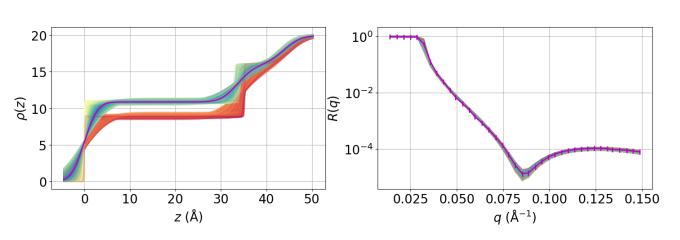
Normalizing flows coupled with MCMC / IS

Corner plot with 4 parameters out of 10



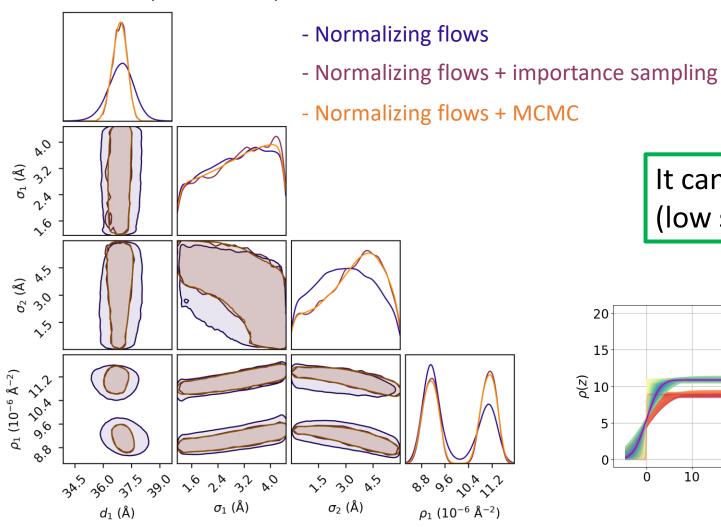
Can be refined to provide **accurate** distribution in mere seconds

Can it miss any modes?



Normalizing flows guarantees revealing all modes [1]

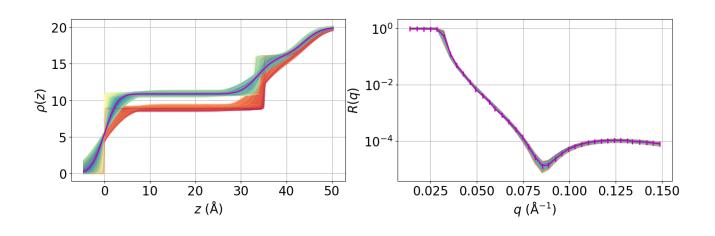
Corner plot with 4 parameters out of 10



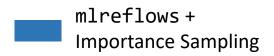
Can be refined to provide **accurate** distribution in mere seconds

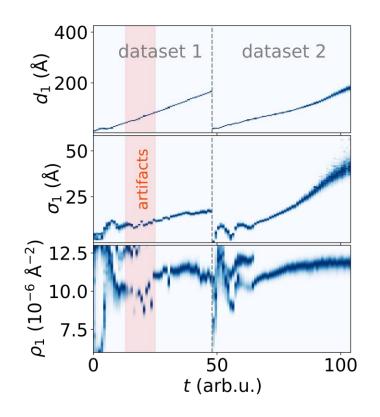
Can it miss any modes?

It can be wider than the correct solution (low sample efficiency), but not narrower

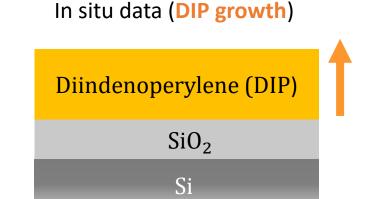


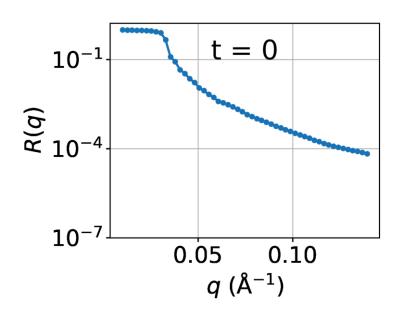
Analysis of experimental *in situ* XRR data: mlreflows vs conventional Bayesian methods



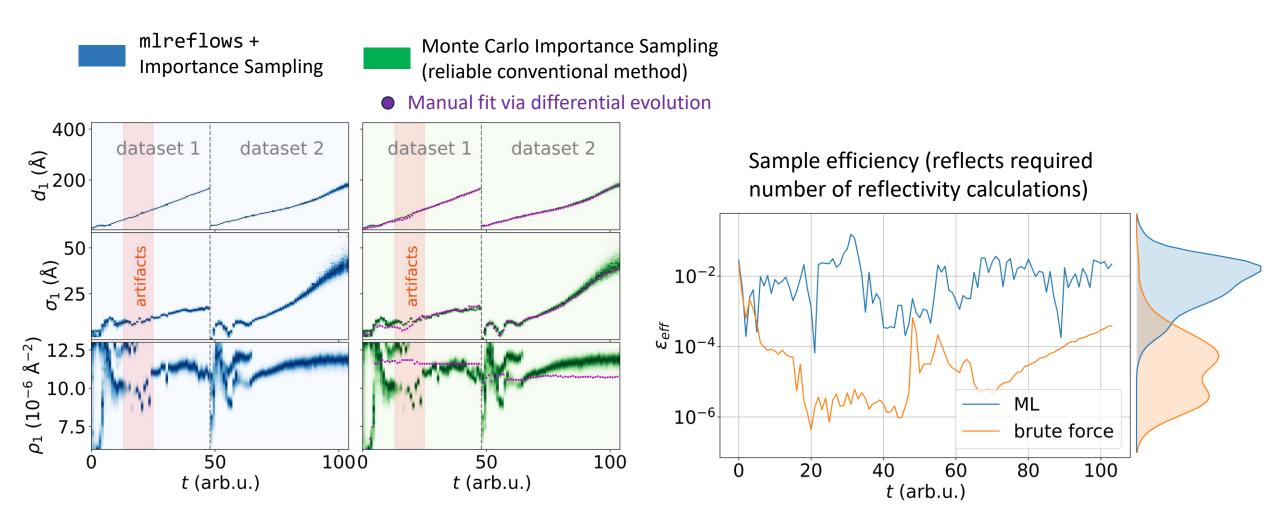


3 open parameters: thickness, roughness, SLD of organic layer



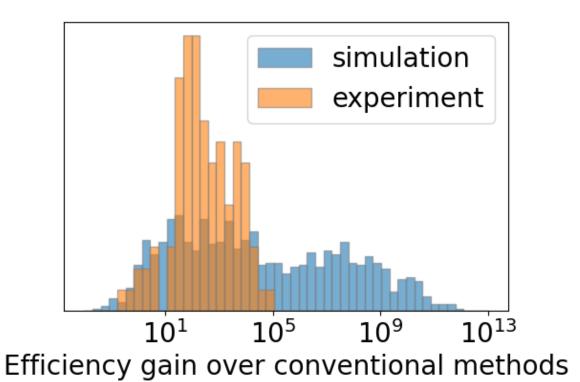


Analysis of experimental *in situ* XRR data: mlreflows vs conventional Bayesian methods



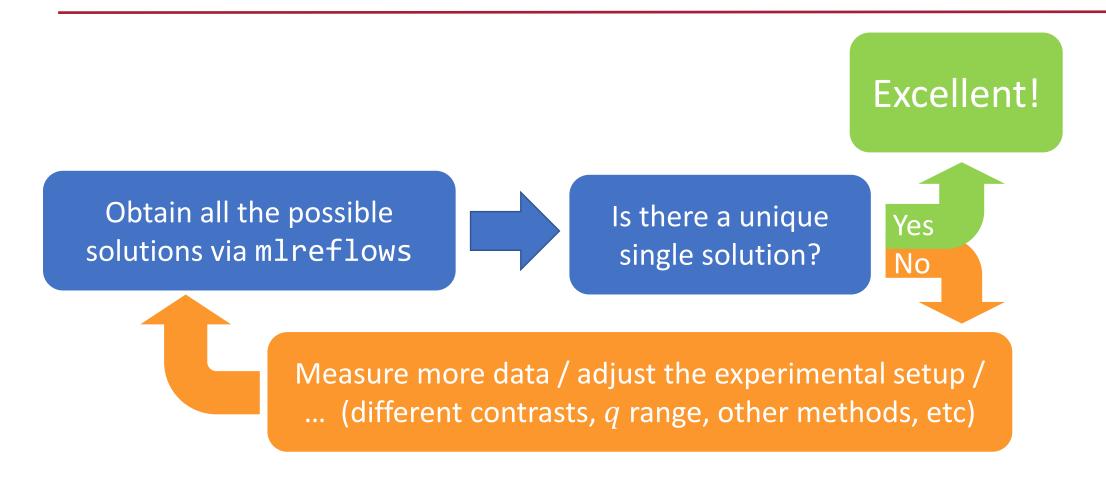
3 open parameters: thickness, roughness, SLD of organic layer

Efficiency gain over conventional methods



More open parameters / wider parameter ranges

Reliable approach to reflectometry analysis



Summary

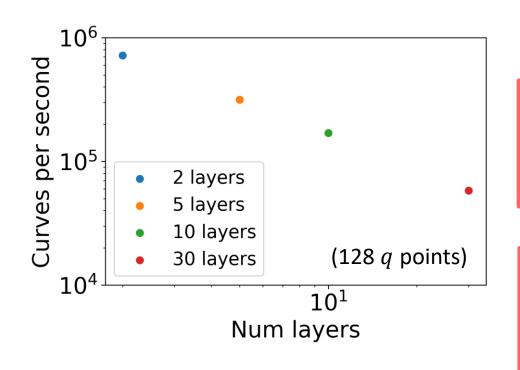
- Ambiguity is one of the main challenges in the reflectometry analysis both for ML and conventional methods
- We present two novel prior-aware ML methods for reflectometry analysis:
 - 1. mlreflect 2.0 a lightweight ML approach fast alternative to conventional fit that can even be trained during the beamtime and works in complex scenarios if priors are narrow enough.
 - 2. mlreflows (3.0) a probabilistic solution based on normalizing flows. Coupled with importance sampling / MCMC, it enables reliable and accurate real-time Bayesian analysis, achieving up to 10^{12} efficiency gain over conventional methods.
- Additionally, we present PyTorch implementation of Abeles & MCMC that speeds up ML training, ML inference, and conventional analysis on GPU.

Supporting Information

How to train NN during a beamtime? GPU implementation of Abeles







Reflectometry simulations (Abeles) in PyTorch:

pprox 100k-1M curves per second (Nvidia GeForce RTX 2080 Ti)

Markov Chain Monte Carlo (MCMC) in PyTorch:

Approx. \times 600 acceleration over CPU (30 min \rightarrow 3 sec)

Training batches are generated on the fly (no validation data required)

1. Generate random params



2. Simulate curve



3. Make prediction with NN



4. Update NN to minimize error

repeat

emcee package [2] in PyTorch – MCMC on GPU

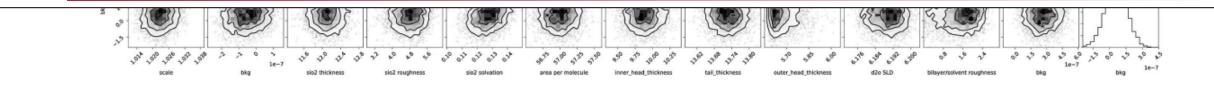


Figure 4

A corner plot for the varying parameters of DMPC bilayers supported on a silicon crystal, measured at three contrasts. The sampling took \sim 33 min on a 2.8 GHz quad-core computer for 20 saved steps, corresponding to 4000 samples, with the steps being thinned by a factor of 400. A larger-scale image is available in the supporting information. Source [1]

GPU implementation allows to reduce 30 minutes to ≈ 3 seconds ($\times 600$ acceleration)

Real-time Bayesian analysis, we just need a good initialization!

Modern GPU (Nvidia GeForce RTX 2080 Ti) + vectorized PyTorch implementation heavily relied on refnx [1]:

 $\approx 100k$ – $\,1M$ curves per second

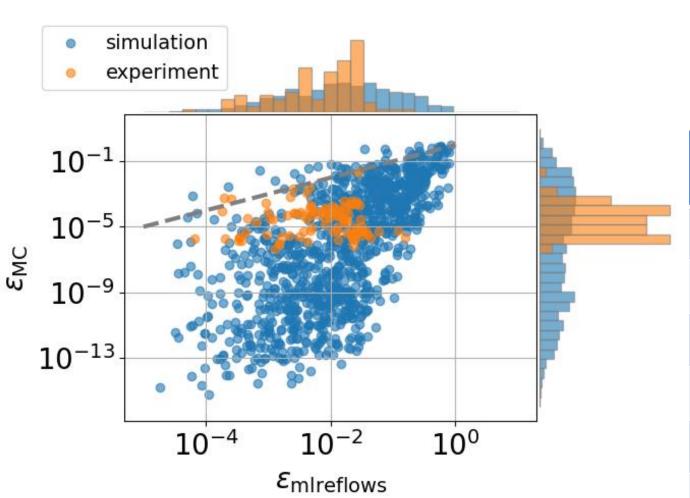
Probably can be pushed further by compiled implementations (JAX, Julia, etc)





[1] Nelson, A. R. J. & Prescott, S. W. (2019). J. Appl. Cryst. 52, 193-200

Efficiency gain over conventional methods

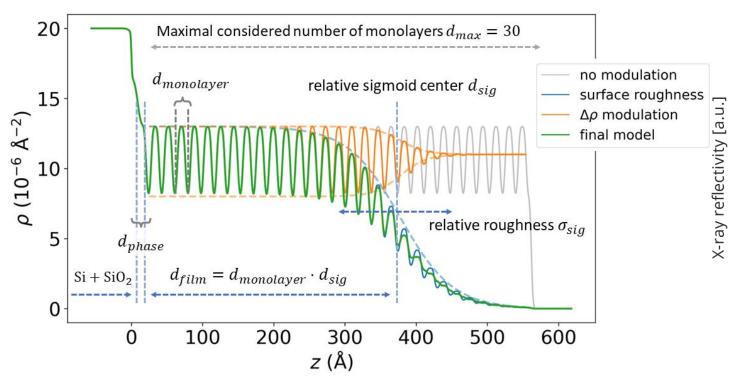


Time estimate for different sample efficiency ϵ (1000 effective samples and **1M curves / sec** speed)

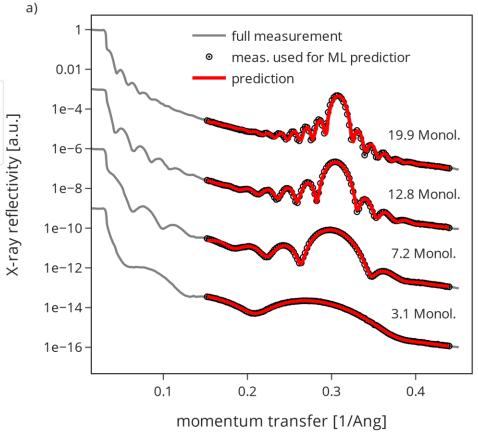
ϵ	Num samples	Time / 1 eff. sample	Total time
$\epsilon = 10^{-2}$	10 ⁵	0.1 ms	100 ms
$\epsilon = 10^{-4}$	10^{7}	10 ms	10 sec
$\epsilon = 10^{-6}$	109	1 sec	17 min
$\epsilon = 10^{-8}$	10 ¹¹	1.5 min	27 hours
$\epsilon = 10^{-10}$	10 ¹³	2.5 hours	120 days
$\epsilon = 10^{-12}$	10 ¹⁵	11 days	30 years

mlreflect 2.0 — fitting Bragg peaks with multilayer parameterization

Parameterization scheme with 17 parameters of periodic monolayer structure



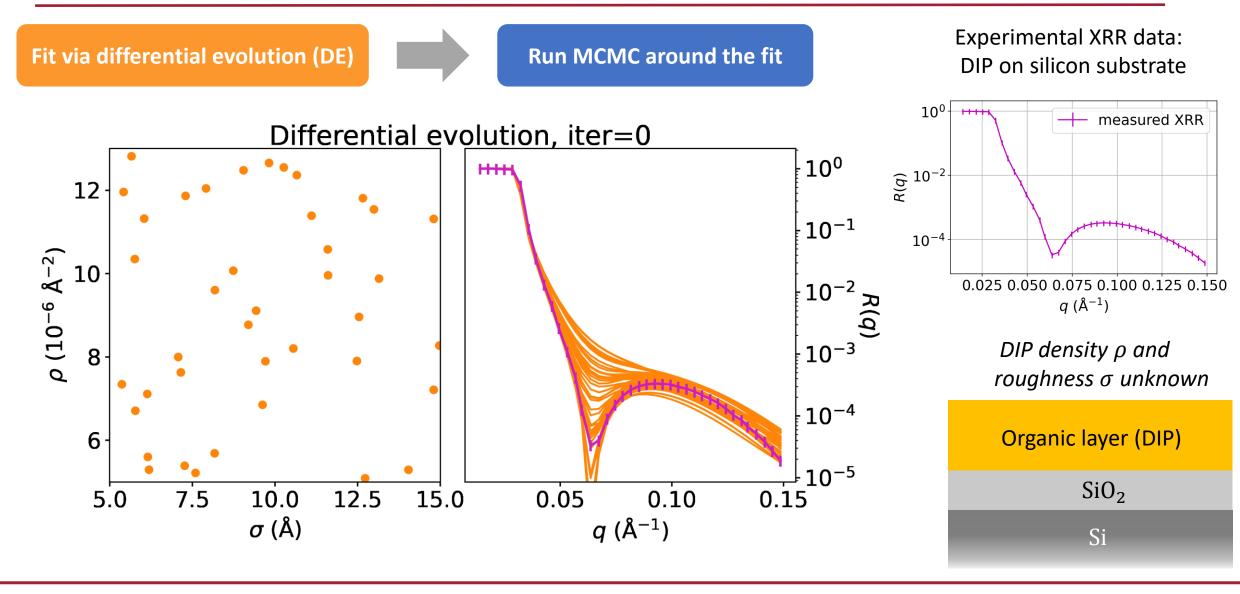
Real-time AI-based fit on in situ experimental data



Conventional methods for Bayesian reflectometry analysis

Sample efficiency and the curse of dimensionality

Conventional algorithms (example with refnx [1])



Conventional methods for Bayesian reflectometry analysis

Find the solution(s)

MCMC does not help – on the opposite, it requires proper initialization

Gradient-based methods are not applicable - they stuck in local minima

Random exploration

- Differential evolution
- Monte Carlo
 Importance Sampling

How long does it take to get reliable result?

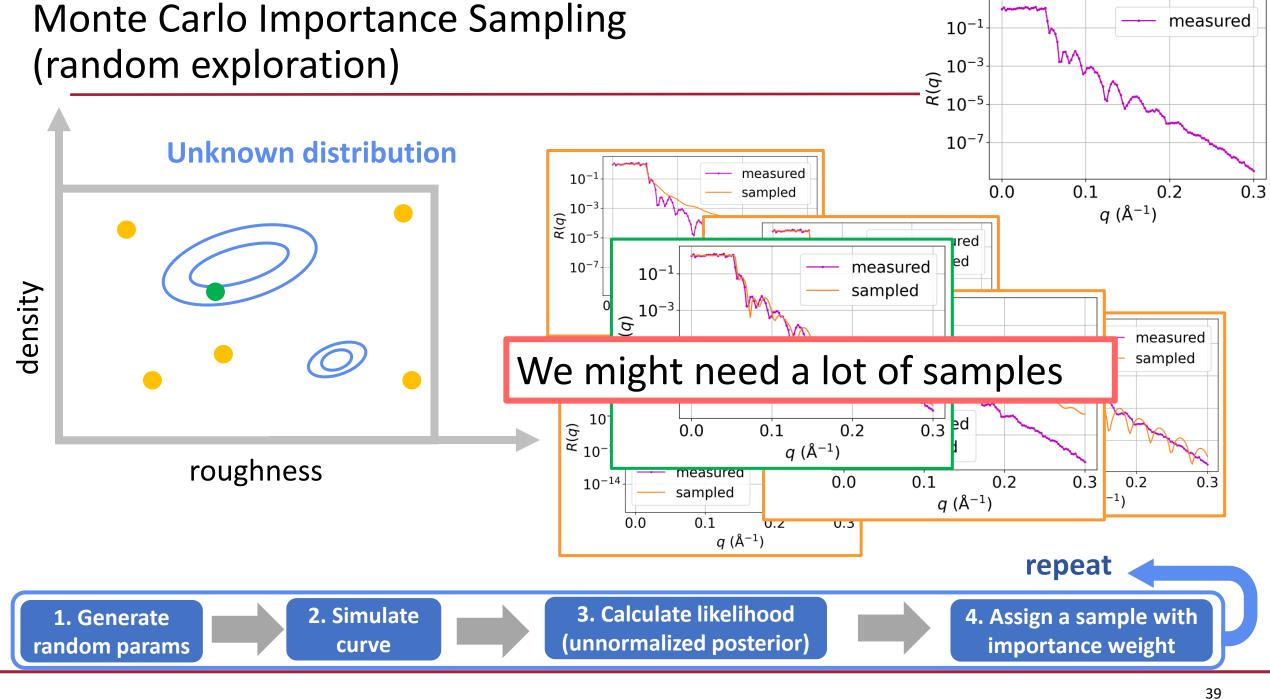
Refine the distribution

Affine Invariant Markov Chain Monte
Carlo

Gradient-based methods (Hamiltonian Monte Carlo, etc.)

... many other methods

Takes seconds / minutes on GPU



Conventional algorithms (example with refnx [1])

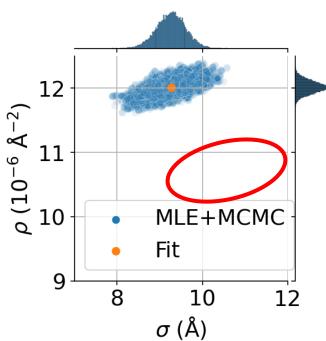
Fit via differential evolution (DE)



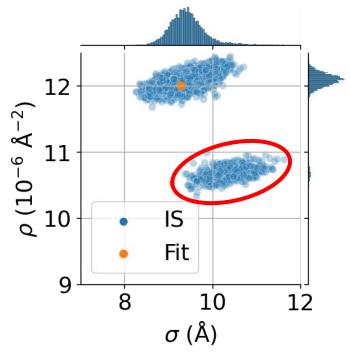
Run MCMC around the fit

MCMC can miss secondary modes depending on initialization [2]

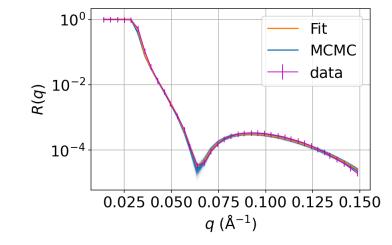
MCMC solution:



Monte Carlo solution:



Experimental XRR data: DIP on silicon substrate



DIP density ρ and roughness σ unknown

Organic layer (DIP)
SiO₂
Si

[2] Robert, C. & Casella, G. Monte Carlo Statistical Methods (2013) Springer Science & Business Media

Conventional algorithms (example with refnx [1])

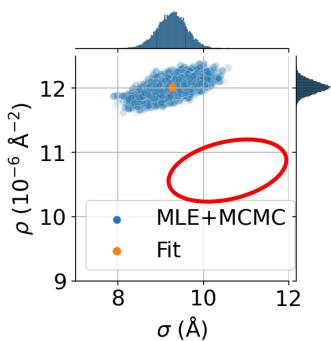
Fit via differential evolution (DE)



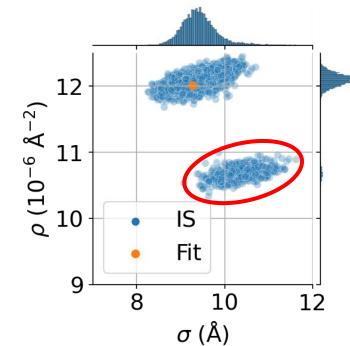
Run MCMC around the fit

MCMC can miss secondary modes depending on initialization [2]

MCMC solution:



Monte Carlo solution:

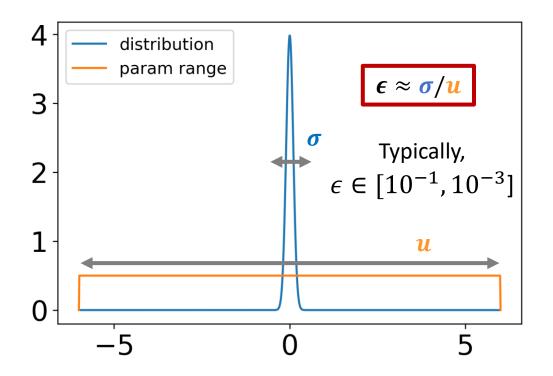


- Differential evolution is not reliable, does not address ambiguity.
- MCMC cannot fix it.
- However, there are conventional method that resolve all the modes.
- Random exploration is the key strategy.

[2] Robert, C. & Casella, G. Monte Carlo Statistical Methods (2013) Springer Science & Business Media

Sample efficiency ϵ for random exploration (MC IS)

 ϵ reflects number of samples required to find solution

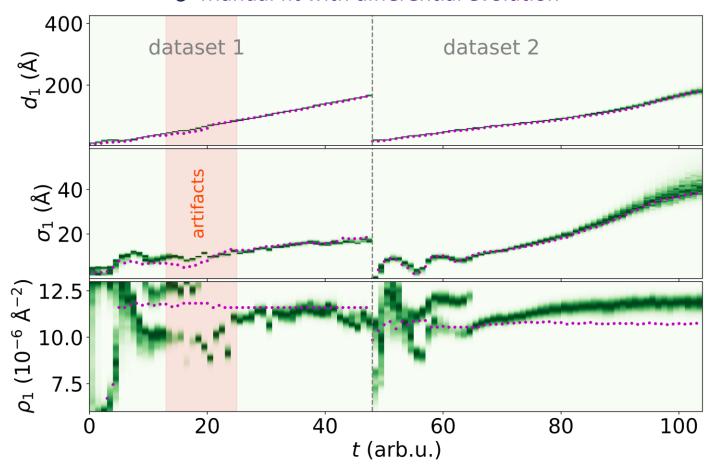


For more open parameters (higher dimensionality), $\epsilon \approx \left(\frac{\sigma}{u}\right)^{dim}$ $\left(\epsilon \in \left[10^{-dim}, 10^{-3*\frac{dim}{dim}}\right]\right)$

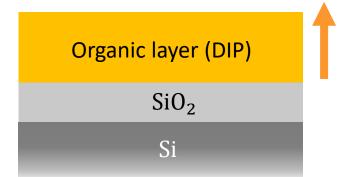
Sample efficiency ϵ on in situ experimental XRR data

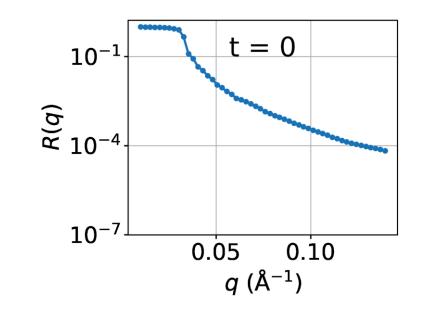
Parameter distributions for thickness, roughness, SLD of DIP (Monte Carlo importance sampling)

Manual fit with differential evolution



In situ data (DIP growth)

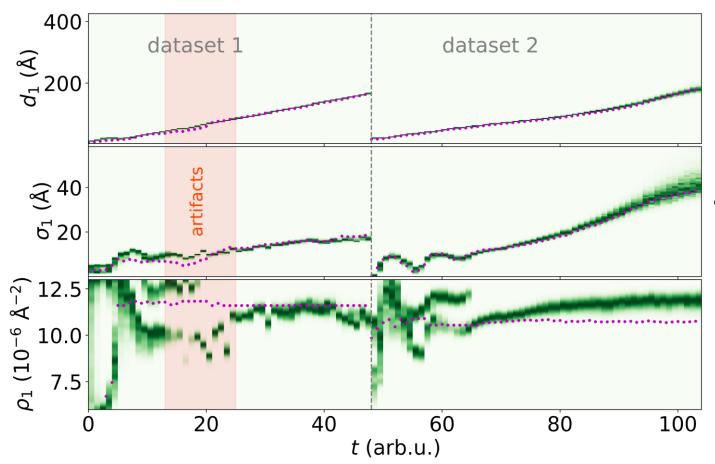




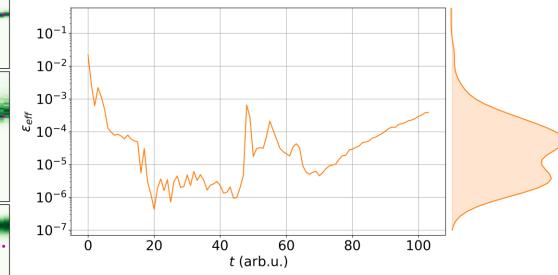
Sample efficiency ϵ on in situ experimental XRR data

Parameter distributions for thickness, roughness, SLD of DIP (Monte Carlo importance sampling)

Manual fit with differential evolution



Monte Carlo sampling efficiency (only 3 open parameters)



Summary on conventional methods

- Conventional analysis primarily relies on random exploration.
- It becomes practically unfeasible **exponentially fast** with increasing number of parameters & parameter ranges.
- Even for a small number of parameters, conventional fits based on differential evolution are unreliable (only find one solution).
- For small number of parameters & narrow bounds, we can use Monte Carlo
- In typical experimental scenarios, sample efficiency is likely to be extremely small.